

<b>Notice of References Cited</b>	Application/Control No. 10/540,501	Applicant(s)/Patent Under Reexamination HAMEAU ET AL.	
	Examiner Shin-Hon Chen	Art Unit 2131	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0236986	12-2003	Cronce et al.	713/189
*	C	US-2004/0103404	05-2004	Naumovich et al.	717/136
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**NON-PATENT DOCUMENTS**

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